

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 240093US-2 DIV		SERIAL NO.	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT TSUNEO KUROTORI, ET AL.			
				FILING DATE HEREWITH		GROUP 2852	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<i>SL</i>	AA	4,052,959	10/1977	Hayashi et al.	<i>399</i>	<i>249</i>	
<i>SL</i>	AB	5,359,398	10/1994	Echigo et al	<i>399</i>	<i>71</i>	
<i>SL</i>	AC	5,374,980	12/1994	Kubo et al.	<i>399</i>	<i>233</i>	
<i>SL</i>	AD	6,219,500	04/2001	Byun, S.	<i>399</i>	<i>57</i>	<i>2/7/00</i>
<i>SL</i>	AE	6,370,347	04/2002	Shin et al.	<i>399</i>	<i>249</i>	<i>8/23/00</i>
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
<i>SL</i>	AO	7-209922	08/11/95	Japan (with English Abstract)		x	
<i>SL</i>	AP	7-152254	06/16/95	Japan (with English Abstract)		x	
	AO	7-21935	01/24/05	Japan (with English Abstract)		x	
<i>SL</i>	AR	2000-47490	02/18/00	Japan (with English Abstract)		x	
<i>SL</i>	AS	2000-242088	09/08/00	Japan (with English Abstract)		x	
<i>SL</i>	AT	2001-228717	08/24/01	Japan (with English Abstract)		x	
<i>SL</i>	AU	01-206379	08/1989	Japan			
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW						
	AX						
	AY						
	AZ						
Examiner <i>Sophia S. Chen</i>					Date Considered <i>1/28/04</i>		

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.